



ALPHA & OMEGA
SEMICONDUCTOR

AO8822

20V Common-Drain Dual N-Channel MOSFET

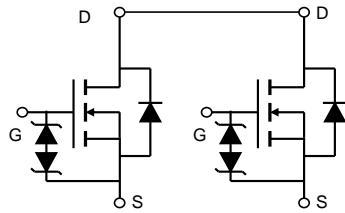
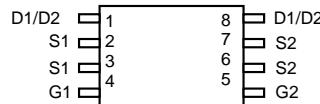
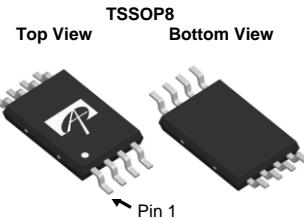
General Description

The AO8822 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 1.8V while retaining a 12V $V_{GS(MAX)}$ rating. This device is suitable for use as a uni-directional or bi-directional load switch, facilitated by its common-drain configuration.

Product Summary

V_{DS}	20V
I_D (at $V_{GS}=10V$)	7A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 18mΩ
$R_{DS(ON)}$ (at $V_{GS} = 4.5V$)	< 22mΩ
$R_{DS(ON)}$ (at $V_{GS} = 3.6V$)	< 23mΩ
$R_{DS(ON)}$ (at $V_{GS} = 2.5V$)	< 27mΩ

ESD Protected



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	20	V
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current	I_D	7	A
$T_A=70^\circ C$		6	
Pulsed Drain Current ^C	I_{DM}	30	
Power Dissipation ^B	P_D	1.5	W
$T_A=25^\circ C$		1	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10s$	R_{0JA}	63	83	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		101	130	°C/W
Maximum Junction-to-Lead	R_{0JL}	64	83	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=20\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 10\text{V}$			10	μA
BV_{GSO}	Gate-Source Breakdown Voltage	$V_{DS}=0\text{V}, I_G=\pm 250\mu\text{A}$	± 12			V
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.5	0.8	1	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	30			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=7\text{A}$ $T_J=125^\circ\text{C}$	13	15	18	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=6.6\text{A}$	15	17	22	
		$V_{GS}=3.6\text{V}, I_D=6\text{A}$	16	18	23	
		$V_{GS}=2.5\text{V}, I_D=5.5\text{A}$	18	21	27	
		$V_{GS}=1.8\text{V}, I_D=2\text{A}$		28		
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=7\text{A}$		31		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.7	1	V
I_S	Maximum Body-Diode Continuous Current				2	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=10\text{V}, f=1\text{MHz}$	520	650	780	pF
C_{oss}	Output Capacitance			140		pF
C_{rss}	Reverse Transfer Capacitance			60		pF
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=10\text{V}, I_D=7\text{A}$	12	15	18	nC
$Q_g(4.5\text{V})$	Total Gate Charge		5	6.7	8	nC
Q_{gs}	Gate Source Charge			3.6		nC
Q_{gd}	Gate Drain Charge			3		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=10\text{V}, R_L=1.5\Omega, R_{\text{GEN}}=3\Omega$		0.25		us
t_r	Turn-On Rise Time			0.45		us
$t_{D(\text{off})}$	Turn-Off Delay Time			11		us
t_f	Turn-Off Fall Time			4		us
t_{rr}	Body Diode Reverse Recovery Time	$I_F=7\text{A}, dI/dt=500\text{A}/\mu\text{s}$	8	10	12	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=7\text{A}, dI/dt=500\text{A}/\mu\text{s}$	8	11	13.5	nC

A. The value of R_{JJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

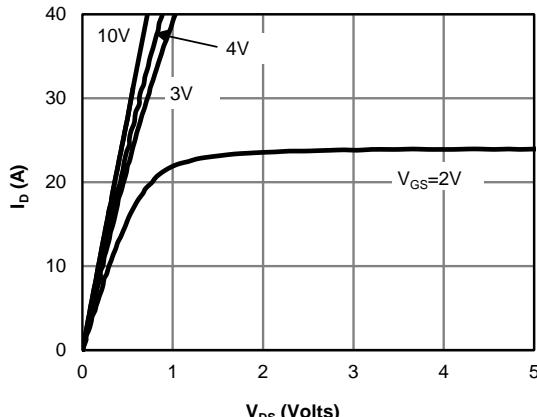
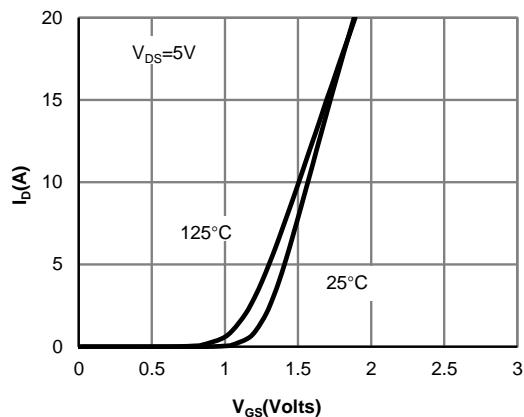
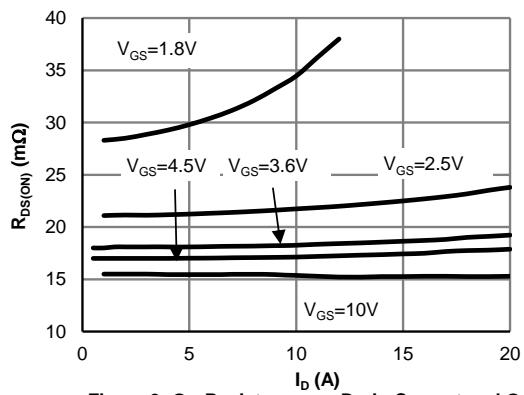
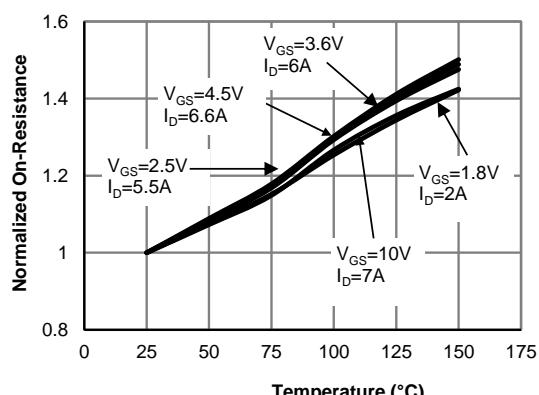
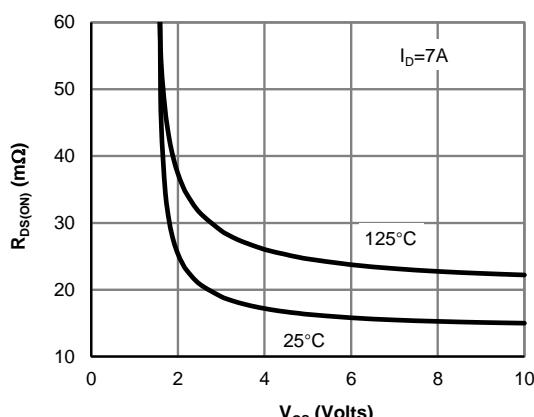
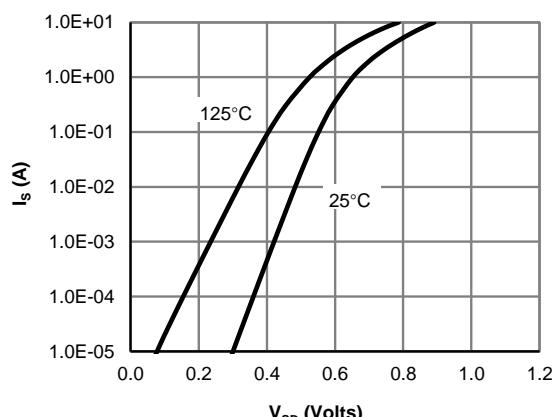
D. The R_{JJA} is the sum of the thermal impedance from junction to lead R_{JUL} and lead to ambient.

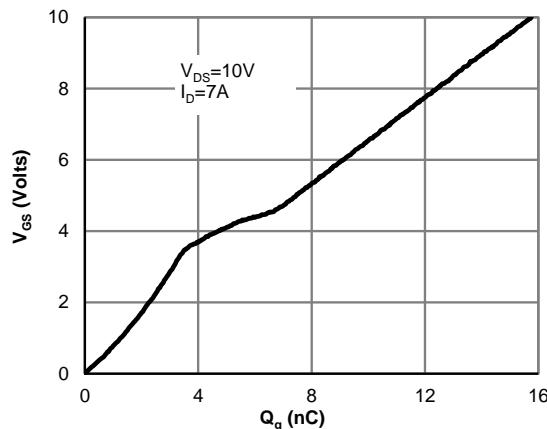
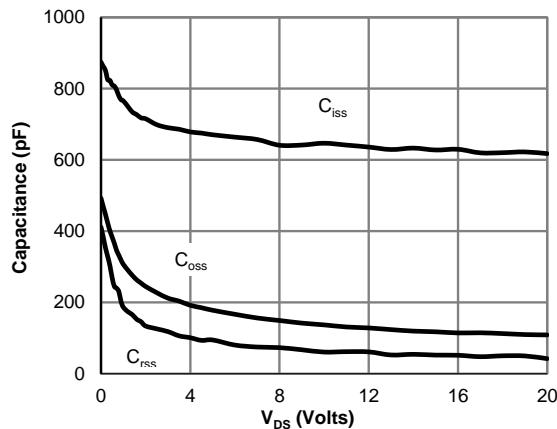
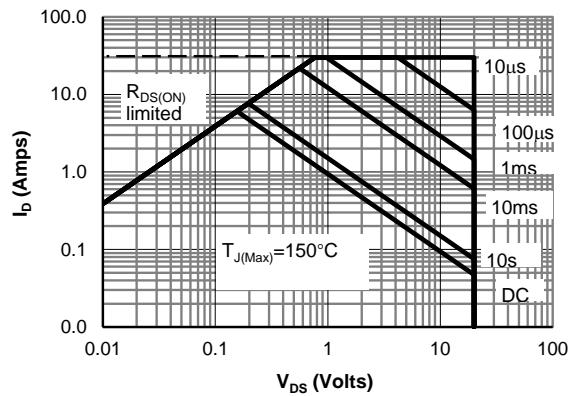
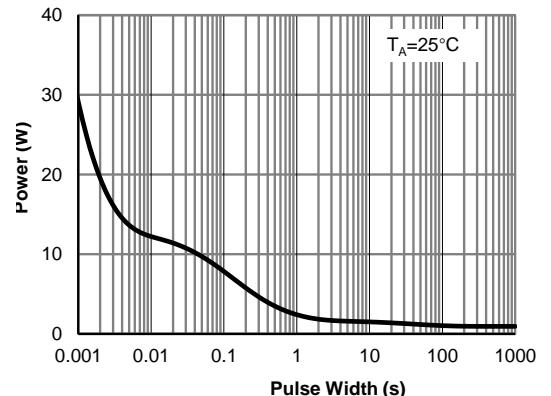
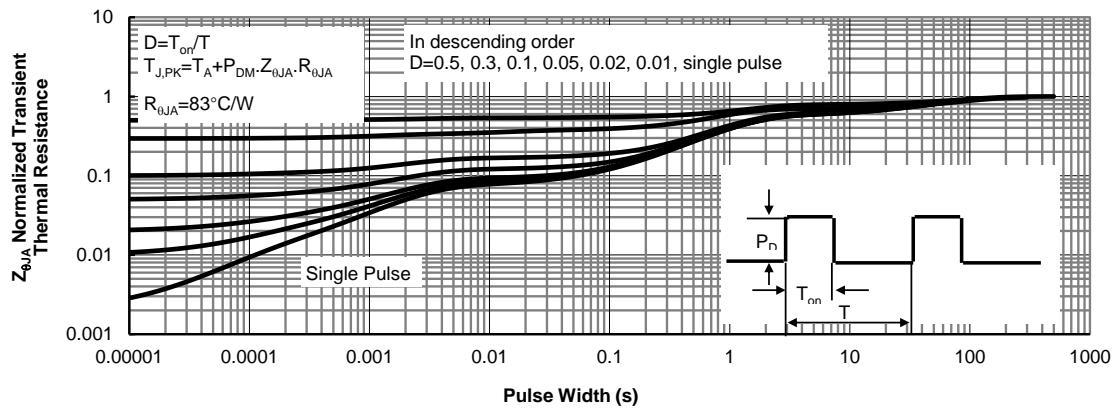
E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

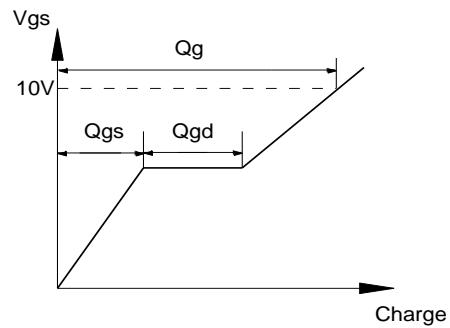
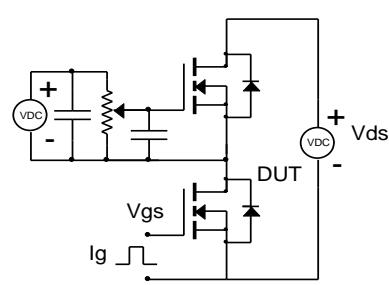
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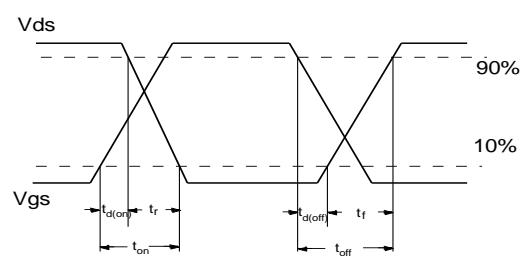
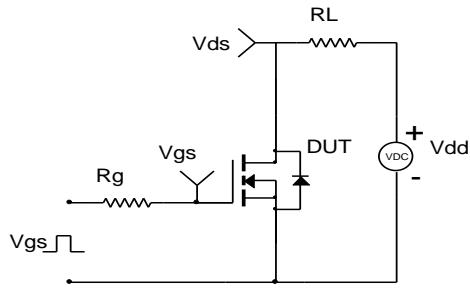
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

